PROCEEDINGS OF SPIE

Anomaly Detection and Imaging with X-Rays (ADIX) VIII

Amit Ashok
Joel A. Greenberg
Michael E. Gehm
Editors

3–4 May 2023
Orlando, Florida, United States

Sponsored and Published by
SPIE

Volume 12531

Proceedings of SPIE 0277-786X, V. 12531

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Anomaly Detection and Imaging with X-Rays (ADIX) VIII, edited by Amit Ashok, Joel A. Greenberg, Michael E. Gehm, Proc. of SPIE Vol. 12531, 1253101 · © 2023 SPIE
0277-786X · doi: 10.1117/12.2690838

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Please use the following format to cite material from these proceedings:
Author(s), "Title of Paper," in *Anomaly Detection and Imaging with X-Rays (ADIX) VIII*, edited by Amit Ashok, Joel A. Greenberg, Michael E. Gehm, Proc. of SPIE 12531, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510661769
ISBN: 9781510661776 (electronic)

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time)
SPIE.org
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Contents

v *Conference Committee*

SYSTEM DESIGN, DEVELOPMENT, AND EVALUATION

12531 02 **CT results using an inverse Compton x-ray source (Invited Paper)** [12531-1]

12531 03 **Performance of a high-throughput full-tunnel XRD checked baggage scanning system** [12531-2]

12531 04 **Classifiers for material discrimination with dual modality x-ray transmission and coherent x-ray diffraction system** [12531-3]

12531 05 **Unique opportunities to sample parameter space using physics-based synthetic x-ray data** [12531-4]

ALGORITHMS I

12531 08 **Intra-class data augmentation with deep generative models of threat objects in baggage radiographs** [12531-8]

ALGORITHMS II

12531 09 **Developing a comprehensive, adaptive system for large-scale x-ray images (Invited Paper)** [12531-9]

12531 0A **Simulation and information-theoretic analysis of hybrid CT+XRD imaging system** [12531-10]

12531 0B **Progressive sequential imaging on x-ray baggage inspection systems** [12531-11]

12531 0C **Position independence for consistent effective atomic number (Z_{eff}) estimation in dual-energy x-rays** [12531-12]

12531 0D **3D threat image projection through dual-energy decomposition** [12531-13]

X-RAY PHASE

12531 0F **Spectrally responsive edge illumination x-ray phase contrast imaging (XPCI)** [12531-15]

12531 0G **Spectral gratings-based phase-contrast imaging for materials characterization** [12531-16]

12531 0I **Asymmetric illumination x-ray differential phase contrast imaging** [12531-18]

X-RAY DETECTORS AND APPLICATIONS

12531 0J **Low-cost XRD detector technology which scales to large FoV (Invited Paper)** [12531-19]

12531 0L **Detector comparison for high-resolution 3D x-ray diffraction imaging for biospecimen analysis** [12531-21]

POSTER SESSION

12531 0M **Semi-supervised anomaly detection algorithm based on KL divergence (SAD-KL)** [12531-22]

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